

AMENDMENTS TO THE CLAIMS

Please amend the claims as follows:

1-41 (cancelled)

42. (currently amended) An analytical system for reflectometric analysis of an analyte in a sample liquid comprising:

a test strip provided with a target surface test field for application of the sample liquid wherein the test field including the applied sample liquid has a target surface;

a measuring head arranged at a distance from the target surface, wherein the measuring head comprises a source for radiating the sample target surface and a detector for measuring radiation reflected by the sample target surface;

an optical triangulation unit for detecting the distance between the measuring head and the target surface, wherein the triangulation unit comprises a light emitter directed towards the target surface in an incidence axis and a light receiver pointing towards the target surface in the direction of a receiving axis and wherein the incidence and receiving axis intercept at a reference point at a specified angle; and

a control device for adjusting the distance between the measuring head and the target surface to a predetermined value, thereby permitting accurate analysis of the analyte by the measuring head.

43. (previously presented) The analytical system as claimed in claim 42, wherein the reference point defines a reference position of the target surface.

44. (previously presented) The analytical system as claimed in claim 42, wherein the incidence and receiving axis enclose different angles relative to a perpendicular on the target surface.

45. (previously presented) The analytical system as claimed in claim 42, wherein the light receiver has a sensor, which is position-resolving at right angles to the receiving axis.

46. (previously presented) The analytical system as claimed in claim 45, wherein the sensor is a PSD sensor, CCD sensor or multi-element diode sensor.

47. (previously presented) The analytical system as claimed in claim 42, wherein the light receiver is a double sensor with two single sensors preferably arranged next to one another and symmetrically to the receiving axis.
48. (previously presented) The analytical system as claimed in claim 42, wherein the light receiver has a collecting optical system whose optical axis defines the receiving axis for focussing the light reflected from the target surface.
49. (currently amended) The analytical system as claimed in claim 42, wherein the light emitter has a light source ~~in particular a point light source~~ and a collimating optical system whose optical axis defines the incidence axis for generating a light beam which is incident on the target surface.
50. (previously presented) The analytical system as claimed in claim 42, wherein the light emitter has a modulation stage for the time-varying actuation of a light source.
51. (previously presented) The analytical system as claimed in claim 42, wherein the light emitter has an edge generator to produce non-linear increasing or decreasing light pulses.
52. (previously presented) The analytical system as claimed in claim 42, wherein the triangulation unit has a signal processing circuit for determining changes in the distance relative to a reference position on the target surface.
53. (previously presented) The analytical system as claimed in claim 52, wherein the signal processing circuit has a comparator and a timer to determine the time interval between specified signal amplitudes of output signals of the triangulation unit.
54. (previously presented) The analytical system as claimed in claim 42, wherein the control device sets the constant measuring distance between the target surface and measuring head by means of a servodrive.
55. (previously presented) The analytical system as claimed in claim 42, further comprising a path measuring device to record the path of the measuring head for determining a height profile of the test object.
56. (previously presented) The analytical system as claimed in claim 55, wherein the path measuring device has a height profile store to identify the test object.

57. (previously presented) The analytical system as claimed in claim 42, further comprising an evaluation unit to standardize the results of the photometric analysis of the triangulation unit on the basis of the distance between the target surface and the measuring head.
58. (currently amended) The analytical system as claimed in claim 42, wherein the light source is at the same time the light emitter ~~and/or~~ or the radiation detector is at the same time the light receiver of the triangulation unit.
59. (currently amended) A method for reflectometric analysis of an analyte in a sample liquid comprising:
- applying the sample liquid to a target surface of a test strip to form a test field having a target surface;
- arranging the target surface at a distance from a measuring head, wherein the measuring head comprises a source for radiating the sample and a detector for measuring radiation reflected by the sample;
- detecting the distance between the measuring head and target surface by means of an optical triangulation unit comprising a light emitter directed towards the target surface in an incidence axis and a light receiver pointing towards the target surface in the direction of a receiving axis; and
- adjusting, by means of a control device, the distance between the measuring head and the target surface to a predetermined value; thereby permitting accurate analysis of the analyte by the measuring head.
60. (currently amended) The method as claimed in claim ~~39~~ 52, wherein the changes in the distance relative to a reference distance of the target surface are detected by means of a corresponding light deflection onto a light receiver of the triangulation unit.
61. (currently amended) The method as claimed in claim ~~39~~ 52, wherein the distance is kept constant at the predetermined value by means of a control device.
62. (previously presented) The analytical system as claimed in claim 42, wherein the light emitter has a modulation stage for the pulsed-shaped actuation of a light source.

63. (previously presented) The analytical system as claimed in claim 42, wherein the light emitter has an edge generator to produce exponentially increasing or decreasing light pulses.